

## ABSTRACT OF THE DISCLOSURE

5 A defect inspection system according to the  
present invention comprises image acquiring section for  
acquiring a two-dimensional image of a subject which is  
a processing target in a manufacturing process, defect  
extracting section for extracting a defect by a defect  
extraction algorithm using a predetermined parameter  
for an image acquired by the image acquiring section,  
displaying section for displaying an image of a defect  
10 of the subject extracted by the defect extracting  
section, parameter adjusting section for adjusting the  
parameter in accordance with a defect extraction degree  
for the subject, and quality judging section for  
judging the quality of the subject based on a defect  
15 information extracted by the defect extracting section.

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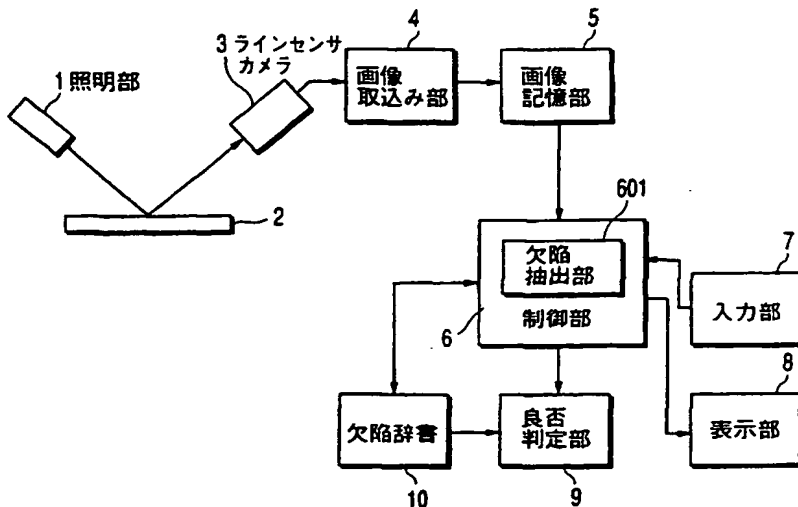
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- (22) 国際出願日: 2000年11月28日 (28.11.2000) (72) 発明者; および (75) 発明者/出願人 (米国についてのみ): 田中利彦 (TANAKA, Toshihiko) [JP/JP]; 〒399-4106 長野県駒ヶ根市東町15番17号 Nagano (JP).
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- (26) 国際公開の言語: 日本語 (74) 代理人: 鈴江武彦, 外(SUZUYE, Takehiko et al.); 〒100-0013 東京都千代田区霞が関3丁目7番2号 鈴榮内外国特許法律事務所内 Tokyo (JP).
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- (71) 出願人 (米国を除く全ての指定国について): オリンパス光学工業株式会社 (OLYMPUS OPTICAL CO.,

[続葉有]

(54) Title: DEFECT INSPECTING SYSTEM

(54) 発明の名称: 欠陥検査システム



(57) Abstract: A defect inspecting system comprising image capturing means for capturing a two-dimensional image of an object to be processed in a manufacturing process, defect extracting means for extracting a defect from the captured image according to a defect extracting algorithm using a predetermined parameter, display means for displaying the image of the defect of the object extracted, parameter adjusting means for adjusting the parameter according to the degree of extraction of the defect of the object, and acceptance/rejection judging means for judging whether or not the object is acceptable according to the information on the extracted defect.

- 1...ILLUMINATING UNIT  
3...LINE SENSOR CAMERA  
4...IMAGE CAPTURING UNIT  
5...IMAGE STORAGE UNIT  
601...DEFECT EXTRACTING SECTION  
6...CONTROL UNIT  
7...INPUT UNIT  
10...DEFECT DICTIONARY  
9...ACCEPTANCE/REJECTION JUDGING UNIT  
8...DISPLAY UNIT

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